

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/020,167	TANAKA, YOSHIKAZU	SHIKAZU	
Examiner	Art Unit		
Steven D. Maki	1733		

	SEARCHED				
Class	Subclass	Date	Examiner		
152	209.1 209.4 209.5 458,531				
156	117				
428	114,156				
	167,172				
	173,220				
	295.1				
	295.4				
174	117F				
24	30.5P				
	30.5T				
updated	above	1/5/2006	Am		
152	451	1/5/2006	Jm		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
PGPUB, USPAT text search - see interference search printout		1/5/2006	Sh		

SE (INCLUDIN)	ARCH NOT	ES STRATEGY	·)
		DATE	EXMR
none		1/5/2006	Jm

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